z-resolution in a TPC with a pixel readout

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LCTPC Analysis meeting

May 18, 2018





Image: A match a ma

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Outline

1 z-resolution in single chip detector





Time stamping resolution of TPC tracks in ILD

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Single chip Timepix3-based GridPix detector

Timepix3-based GridPix:

- Micro-pattern gaseous detector with grid aligned to pixels
- 65K 55 μm \times 55 μm sized pixels

Timepix3 compared to its predecessor:

- Improved time resolution of 1.56 ns
- Simultaneous time and charge (ToT) measurement

Single chip Timepix3 detector with field shaping, guard electrode, and T2K TPC gas (Ar:CF₄:iC₄H₁₀ 95:3:2)





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Test beam measurements

- Test beam using 2.5 GeV electrons at the ELSA facility (Bonn)
- Tracks are reconstructed by simple linear regression
- Drift field is 280 V/cm
 - $v_{\rm drift} = 78.86(1) \, \mu m/ns$ from Magboltz

111.3 mm 16.0 mm



Image: A match a ma

18.25 mm

15.45 mm

Mimosa

Scintillator

Beam

2.65 mm 💭 12.35 mm

TPC

Timepix3

374 mm

15.8 mm

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Time walk correction

Time walk error is caused by ToA depending on signal magnitude This can be corrected using



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z-resolution

Resolution σ_z determined by longitudinal diffusion coefficient D_L and resolution at zero drift distance σ_{z0} : $\sigma_z^2 = \sigma_{z0}^2 + D_L^2(z - z_0)$



Measured $D_L = 226 \,\mu\text{m}/\sqrt{\text{cm}}$ (Magboltz predicts 201(5) $\mu\text{m}/\sqrt{\text{cm}}$) and $\sigma_{z0} = 139 \,\mu\text{m}$ (168 μm if including ToT < 0.60 μ s)

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ToT error is propagated to z-resolution

ToT error $\sigma_{ToT} = k_0 + k_1(t_{ToT} + t_0)$ causes error in *z*-position through time walk correction.

Fit $\sigma_{z0}^2 = \sigma_{ToT}^2 + \sigma_0^2$ for slices in ToT of width 0.05 µs



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Contributions to *z*-resolution

Contributions at zero drift distance

Time resolution: $\tau v_{drift}/\sqrt{12}$	34 µm
Systematics of the chip from a histogram	47 µm
Uncertainty in track position	30 µm
Fluctuations in ToT	
(117 μ m for asymptotically high ToT)	154 µm
Total σ_{z0}	168 µm

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Simulation of ILD TPC with pixel readout

- Pixel geometry is implemented in ILD DD4hep simulation (Geant4)
- $\bullet\,$ Simulated in layers of ${\sim}990\,\mu m$ over which to track is interpolated to $55\,\mu m$ pixels
- An energy deposit is converted to a hit if above 27 eV (Our tune)
- Hits are smeared with hit-resolution

•
$$\sigma_z = \sqrt{\sigma_{z0}^2 + D_z^2 z_{\text{drift}}}$$

- From test beam: $\sigma_{z0} = 0.168 \text{ mm}$
- From Magboltz: $D_L = 205 \,\mu\text{m}/\sqrt{\text{cm}}$ (test beam $D_L = 226 \,\mu\text{m}/\sqrt{\text{cm}}$)
- Tracks are reconstructed with a Kalman filter



Contributions to the z-resolution

Uncertainty from position measurement

$$\sigma_{\rm me}^2 = \frac{\sigma_z^2}{\sqrt{N}} \propto \frac{\sigma_z^2}{\sqrt{L_{\rm track}}} \tag{2}$$

• Uncertainty from weighted measurement of angle

$$\frac{1}{\sigma_{\rm ms}^2} \propto \frac{1}{\sigma_0^2} + \frac{p^2}{\sigma_1^2 L^3} \Rightarrow \sigma_{\rm ms}^2 \propto \frac{1}{1/\sigma_0^2 + p^2/(\sigma_1^2 L^3)},\tag{3}$$

where the first term captures the measurement error and the second term the multiple scattering

Equations under the assumption of constant hit errors (diffusion is missing)

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Resolution as a function of angle

for muons



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Resolution as a function of angle

for muons



Parameters are set to $\sigma_z = 64 \,\mu\text{m}$, $\sigma_0 = 76 \,\mu\text{m}$, $\sigma_1 = 87 \,\mu\text{m}(\text{GeV/c})^{-1} \text{m}_{\text{Nik/hef}}^{-3}$

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Resolution as a function of momentum

for muons



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z-resolution as a function of momentum

for muons



Parameters are set to $\sigma_z = 64 \,\mu\text{m}$, $\sigma_0 = 76 \,\mu\text{m}$, $\sigma_1 = 87 \,\mu\text{m}(\text{GeV/c})^{-1} \text{m}_{\text{Nikkbar}}^{-3}$

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$Cot(\theta)$ resolution

for muons



z-resolution in the ILD TPC with pixel readout

	At inner radius	At outer radius
50 GeV muons at 85°	50 µm	50 µm
50GeV muons at 25°	13 µm	35 µm
2 GeV muons at 85°	75 µm	75 µm
2 GeV muons at 25°	25 µm	85 µm
	Without systematics errors	

If instead of the Magboltz value of $D_L = 205 \,\mu\text{m}/\sqrt{\text{cm}}$ the diffusion coefficient $D_L = 226 \,\mu\text{m}/\sqrt{\text{cm}}$ from the test beam setup is used, σ_z is approximately 10% greater: e.g. $\sigma_z = 55 \,\mu\text{m}$ for 50 GeV muons at 85°

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Time stamping of TPC tracks in ILD

Tracks are time stamped by comparing their absolute z-position from the silicon trackers with the z-position determined from the drift time measurement in the TPC

The Silicon Internal Tracker (SIT) and the Silicon External Tracker (SET) will be build from respectively 2 and 1 layers of the same double strip planes with a $\sigma_z = 50 \,\mu\text{m}$ resolution. So the SIT and SET resolution is approximately $50/\sqrt{2}\mu\text{m} = 35 \,\mu\text{m}$ and $50 \,\mu\text{m}$ respectively

The precision of the silicon trackers and hit resolution put stringent requirements on the relative precision of the drift velocity. In a study for the CLIC ILD detector the relative precision from electric field, temperature and pressure was estimated to be $7 \cdot 10^{-6}$, corresponding to $16 \,\mu m^{-1}$

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Time stamping of TPC tracks in ILD



Assuming uncertainties of $16 \,\mu\text{m}$ from the drift velocity, $35 \,\mu\text{m}$ from the SIT, and $50 \,\mu\text{m}$ from the SET. Multiple scattering from inner and outer TPC field was neglected

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Time stamping of TPC tracks in ILD

If the SIT is instrumented with Silicon pixels instead of Silicon strips, the time resolution can be improved



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Conclusion

- From test beam measurements sources of position errors in the z-direction are identified
- The uncertainty in a single chip Gridpix detector is given by $\sigma_z = \sqrt{\sigma_{z0}^2 + D_L^2 z}$, where $\sigma_{z0} = 168 \,\mu\text{m}$ and $D_L = 226 \,\mu\text{m}/\sqrt{\text{cm}}$
- The z-resolution of the ILD TPC with pixel readout is studied and from simulations found to be between $13\,\mu m$ and $85\,\mu m$
- The time stamping resolution of the ILD TPC is estimated to range from 0.65 ns to 1.2 ns

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The TPC as a time of flight detector

Time difference of particles is given by

$$\Delta t = \frac{Lc}{2p^2} (m_1^2 - m_2^2) \tag{4}$$

- Time resolution does not suffice for particle identification (for a 2 GeV/c proton/kaon at traversing the ILD TPC at 45° $\Delta t = 0.632 \text{ ns}$)
- But is useful in searches

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Time walk correction



Timewalk corrected with $z_{tw} = \frac{c_1}{t_{T_0T}+t_0}$ The error in the ToT should be propagated to the *z*-coordinate: $\sigma_z^2 = (\sigma_{z0}(t_{T_0T}))^2 + D_L^2(z-z_0)$

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Propagation of ToT error to σ_z

Propagate error:

$$\sigma_{z0}(t_{\text{ToT}}) = \sigma_{ToT} \frac{\partial z_{tw}}{\partial t_{ToT}}$$
(5)

Derivative is:

$$\frac{\partial z_{tw}}{\partial t_{T_{0}T}} = -c_1 (t_{T_{0}T} + t_0)^{-2}$$
(6)

Assume:

$$\sigma_{ToT} = k_0 + k_1(t_{ToT} + t_0) \tag{7}$$

Full error becomes:

$$\sigma_z(t_{T_oT}) = \sqrt{\frac{(k_0 + k_1(t_{T_oT} + t_0))^2 c_1^2}{(t_{T_oT} + t_0)^4} + \sigma_0^2}$$
(8)

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